

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	10600087	MARUYA, MAKOTO	
	Examiner	Art Unit	
	Chawan, Sheela C	2624	

SEARCHED

Class	Subclass	Date	Examiner
382	144,154,	1/7/07	SCC
370	538,465,385,	1/7/07	SCC
348	42,145,169,143,144	1/7/07	SCC
351	57,158	1/7/07	SCC
124	87	1/7/07	SCC

SEARCH NOTES

Search Notes	Date	Examiner
EAST, US-PGPUB,USPAT,EPO,JPO,DERWENT,IBM-TDB.	1/7/07	SCC
INVENTOR NAME SEARCH.	1/7/07	SCC

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner